

Title (en)

DESIRED WAVE/INTERFERENCE POWER RATIO MEASURING CIRCUIT AND DESIRED WAVE/INTERFERENCE POWER RATIO MEASURING METHOD

Title (de)

SCHALTUNG UND VERFAHREN ZUR MESSUNG DES VERHÄLTNISSSES VON GEWÜNSCHTER WELLENLEISTUNG ZUR STÖRLEISTUNG

Title (fr)

CIRCUIT ET METHODE DE MESURE DU RAPPORT ONDE DESIREE/PUISSANCE DES PARASITES

Publication

**EP 1239615 A1 20020911 (EN)**

Application

**EP 01981046 A 20011109**

Priority

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- JP 2000341648 A 20001109

Abstract (en)

A bias error in a low SIR area is corrected by subtracting a value of an interference signal power multiplied by a first correction coefficient which has been determined from an SIR characteristic diagram obtained in advance from a desired signal power to remove an interference signal component included in the desired signal power. Also, a bias error in a high SIR area is corrected by subtracting a value of a desired signal power multiplied by a second correction coefficient which has been determined from the SIR characteristic diagram obtained in advance from an interference signal power to remove a desired signal component included in the interference signal power. <IMAGE>

IPC 1-7

**H04B 17/00**

IPC 8 full level

**G01R 29/00** (2006.01); **G01R 29/26** (2006.01); **H04B 7/26** (2006.01); **H04B 17/00** (2006.01); **H04B 17/336** (2015.01); **H04W 24/00** (2009.01); **H04W 88/00** (2009.01)

CPC (source: EP US)

**H04B 17/21** (2015.01 - EP US); **H04B 17/336** (2015.01 - EP US)

Citation (search report)

See references of WO 0239626A1

Cited by

EP1639837A4; EP2156599A4; EP1859548A4; WO2005006779A2; US8559895B2; WO2009154590A3; WO2006105297A3; WO2005125066A1; US8503328B2; US8599972B2; WO2006088259A1; US7558576B2

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